

# Citations for Ion : S

<b>Pub. Year</b>	<b>Authors, Title, Journal Citation and Comments</b>	<b>Citation Numb</b>
<b>1966</b>	Bethge, K. Sandner, P. Schmidt, H. <b>'Energieverluste und Ladungszustände Schwerer Ionen Beim Durchgang Durch Materie'</b> <i>Z. Naturforschg. 21A, 1052-57 (1966)</i> Comment : S. 5-20 MeV B, 5-30 MeV O, 7-28 MeV N, 5-30 MeV S -> Ni, Ag, Au	1966-Beth
<b>1966</b>	Fastrup, B. Hvelplund, P. Sautter, C. A. <b>'Stopping Cross Section in Carbon of 0.1-1.0 MeV Atoms with 5&lt;Z&lt;20'</b> <i>Kgl. Danske Videnskab. Selskab. Mat. Fys. Medd., 35, No. 10, 1-28 (1966)</i> Comment : S. (80-900 keV) H, C, N, O, F, Ne, Na, Mg, Al, Si, P, S, Cl, Ar->C	1966-Fast
<b>1968</b>	Armitage, B. H. Hooton, B. W. <b>'Energy Loss of Oxygen and Sulphur Ions in Matter'</b> <i>Nucl. Inst. Methods, 58, 29-35 (1968)</i> Comment : S. 10-30 MeV O, 19-40 MeV S -> Ag, Au	1968-Armi
<b>1968</b>	Bowman, W. W. Lanzafame, F. M. Cline, C. K. Yu, Yu-Wen Blann, M. <b>'Recoil Ranges of 0.2 - 5.2 MeV Ions in Vanadium, Nickel, Iron, Zirconium and Gold.'</b> <i>Phys. Rev., 165, 485-93 (1968)</i> Comment : R, dR. Ion(Z1=12-81, E=0.22-5.2 MeV) -> V, Ni, Zr, Au	1968-Bowm
<b>1968</b>	Fastrup, B. Borup, A. Hvelplund, P. <b>'Stopping Cross Section in Atmospheric Air of 0.2 - 0.5 MeV Atoms with 6 &lt;= Z1 &lt;= 24.'</b> <i>Can. J. Phys., 46, 489-95 (1968)</i> Comment : S. (100-1000 keV) C, N, O, Ne, N, Mg, P, S, Cl, Sc, Ca, Ti Al, Ar, K, Cr -> Air	1968-Fast
<b>1968</b>	Pierce, T. E. Blann, M. <b>'Stopping Powers and Ranges of 5-90 MeV S32, Cl35, Br79, and I127 Ions in H2, He, N2, Ar, and Kr: a Semiempirical Stopping Power Theory for Heavy Ions in Gases and Solids'</b> <i>Phys. Rev., 173, 390-405 (1968)</i> Comment : S. 5-90 MeV 32S, 35Cl, 79Br, 127I -> H2, He, N2, Ar, Kr	1968-Pier
<b>1968</b>	Pierce, T. E. Bowman, W. W. Blann, M. <b>'Stopping Power of S32, Cl35, Br79 and I127 Ions in Mylar'</b> <i>Phys. Rev., 172, 287-91 (1968)</i> Comment : S. 15-95 MeV 32S, 35Cl, 30-90 MeV 79Br, 60-105 MeV 127I -> Mylar	1968-Pier2
<b>1969</b>	Bottiger, J. Bason, F. <b>'Energy Loss of Heavy Ions Along Low-Index Directions in Gold Single Crystals'</b> <i>Rad. Effects, 2, 105-10 (1969)</i> Comment : S. (300-970 keV) N, Ne, Na, Mg, S, Cl, Ar, K, Si, Mn, Fe, Kr, Y, Mo, Ag, Cd, Sb, Xe -> Au	1969-Bott

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<b>1969</b>	Macdonald, J. R. Sidenius, G. <b>'The Total Ionization in Methane of Ions with <math>1 \leq Z \leq 20</math> at Energies from 10 to 120 keV'</b> <i>Phys. Letters A, 28, 543-44 (1969)</i> <i>Comment : S, 10-120 keV H, He, Li, Be, B, C, N, O, F, Ne, Na, Mg, Al, Si, P, S, Cl, Ar, Ca, V, Sc, Ti -&gt; CH4</i>	<b>1969-Macd</b>
<b>1970</b>	Dearnaley, G. Wilkens, M. A. Goode, P. D. Freeman, J. H. Gard, G. A. <b>'The Range Distribution of Radioactive Ions Implanted into Silicon Crystals'</b> <i>W. Palmer, M. W. Thompson, P. D. Townsend: Atomic Collision Phenomena in Solids. North-Holland, Amsterdam, P. 623-55 (1970)</i> <i>Comment : R, dR. 40-120 keV P, Na, S, Cu, Kr -&gt; Si, Cryst. and Amorph.</i>	<b>1970-Dear2</b>
<b>1970</b>	Whitton, J. L. Carter, G. <b>'The Implantation Profiles of Energetic Heavy Ions in GaAs, GaP, and Ge'</b> <i>W. Palmer, M. W. Thompson, P. D. Townsend: Atomic Collision Phenomena in Solids. North-Holland, Amsterdam, 615-32 (1970)</i> <i>Comment : R, dR. 10-40 keV S, Kr, Na -&gt; GaAs,</i>	<b>1970-Whit</b>
<b>1971</b>	Dearnaley, M. A. Wilkins, M. A. Goode, P. D. <b>'Non-Gaussian Implantation Profiles'</b> <i>Intl. Conf. Ion Implantation in Semiconductors, Ed. by I. Ruge and J. Graul, 439-454 (1971)</i> <i>Comment : R, 40-120 keV S, P -&gt; Si</i>	<b>1971-Dear</b>
<b>1971</b>	Whitton, J. L. Bellavance, G. R. <b>'Ion Implantation of Sulphur into GaAs, GaP and Ge Monocrystals'</b> <i>Rad. Effects, 9, 127-31 (1971)</i> <i>Comment : R, dR. 20-40 keV S -&gt; GaAs (Cryst. Axial And Random)</i>	<b>1971-Whit</b>
<b>1975</b>	Bill, U. Sizmann, R. Varelas, C. Rehn, K. E. <b>'Transition of Axial to Planar Channeling'</b> <i>Rad. Effects, 27, 59-66(1975)</i> <i>Comment : S, dS. 100 MeV S -&gt; Si (Cryst.)</i>	<b>1975-Bill</b>
<b>1975</b>	Lyons, R. P. Ehret, . E. Park, Y. S. <b>'Ion Implantation of Diatomic Sulpher into GaAs'</b> <i>Bull. Am. Phys. Soc., 20, 318 (1975)</i> <i>Comment : R. About 100 keV S2 -&gt; GaAs.</i>	<b>1975-Lyon</b>
<b>1976</b>	Comas, J. Plew, L. <b>'Beryllium and Sulfur Ion-Implanted Profiles in GaAs'</b> <i>J. Elec. Mater., 5, 209-221 (1976)</i> <i>Comment : R. 100, 200 keV Be, S -&gt; GaAs</i>	<b>1976-Coma</b>

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1976	Eisen, F. H. Welch, B. M. <b>'Radiotracer Profiles in Sulfur Implanted GaAs'</b> <i>Ion Implantation in Semiconductors, Ed. by F. Chernow, J. A. Borders, D. K. Brice, 97-106 (1976)</i> Comment : R. 100 keV 35S -> GaAs	1976-Eise
1976	Forster, J. S. Ward, D. Andrews, H. R. Ball, G. C. Costa, G. J. <b>'Stopping Power Measurements for 19F, 24Mg, 27Al, 32S and 35Cl at Energies 0.2 to 3.5 MeV/Nucleon in Ti, Fe, Ni, Cu, Ag and Au.'</b> <i>Nucl. Inst. Methods, 136, 349-59 (1976).</i> Comment : S. 2.2 MeV H, 0.2-3.5 MeV/amu F, Mg, Al, S, Cl -> Ti, Fe, Ni, Cu, Ag, Au	1976-Fors
1976	Grob, A. Grob, J. J. Siffert, P. <b>'Energy Loss and Straggling of Heavy Ions by Nuclear Interactions in Silicon'</b> <i>Nucl. Inst. Methods, 132, 273-79 (1976)</i> Comment : S, dS, Eta(Epsilon). 300-2000 keV C, N, O, Ne, Si, S, Ar -> Si	1976-Grob
1977	Anttila, A. Bister, M. Fontell, A. Winterbon, K. B. <b>'Ranges of Some Light Ions Measured by (p,gamma) Resonance Broadening'</b> <i>Rad. Effects, 33, 13-19 (1977)</i> Comment : R. 20-100 keV 13C, 23Na, 26Mg, 27Al, 34S -> Ta; 29Si -> Al	1977-Antt
1977	Molnar, B. Kennedy, T. A. <b>'GaAs Ion-Implantation Parameters Studied through Contactless Mobility Measurements'</b> <i>Electrochem. Soc. Extended Abstracts, 261-262, May (1977)</i> Comment : R. 120 keV S -> GaAs	1977-Moln
1978	Alexander, T. K. Forster, J. S. Ball, G. C. Davies, W. G. Winterbon, K. B. <b>'Z1 and Z2 Variations in the Stopping Powers of Z1=10-18 Ions Deduced from DSAM Lifetime Measurements'</b> <i>Phys. Letters, 74B, 183-186 (1978)</i> Comment : S. Ne, Na, Mg, Al, Si, P, S, Ar (3-4 MeV) -> Cu, Ni, Ta, Au, Mg, Ca, Ti, Ba. Doppler shift lifetime measurements.	1978-Alex
1979	Andrews, H. R. Lennard, W. N. Mitchell, I. V. Ward, D. Phillips, D. <b>'Low Energy Stopping Powers Determined by Time of Flight Techniques'</b> <i>IEEE Trans. Nucl. Sci., NS-26, 1326-1330 (1979)</i> Comment : S. (0.180 < vel. < 0.219 cm/ns) (6 <= Z1 <= 20) -> C, Al, Ni, Ag, Au	1979-Andr
1979	Lorenzo, J. P. Davies, D. E. Ryan, T. G. <b>'Anodic Oxidation and Electrical Carrier Concentration Profiles of Ion-Implanted InP'</b> <i>J. Electrochem. Soc., 126, 118-121 (1979)</i> Comment : R, dR. 1 MeV S, Si -> InP	1979-Lore

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<b>1979</b>	Magee, C. W. <b>'Depth Profiling of N-Type Dopants in Si and GaAs using Cs+ Bombardment Negative Secondary Ion Mass Spectrometry in Ultrahigh Vacuum'</b> <i>J. Electrochem. Soc., 126, 660-663 (1979)</i> <i>Comment : R, dR. 15 keV H, 80 keV P, 200 keV As -&gt; Si; 200 keV Si, 250 keV S -&gt; GaAs</i>	<b>1979-Mage</b>
<b>1979</b>	Park, Y. S. Grant, J. T. Haas, T. W. <b>'The Determination of Sulfur-Ion-Implantation Profiles in GaAs using Auger Electron Spectroscopy'</b> <i>J. Appl. Phys., 50, 809-812 (1979)</i> <i>Comment : R, dR. 60, 120 keV S+, S2+ -&gt; GaAs</i>	<b>1979-Park</b>
<b>1979</b>	Santry, D. C. Werner, R. D. Westcott, O. M. <b>'The Range of 120 keV Ions in Solids'</b> <i>IEEE Trans. Nucl. Sci., Ns-26, 1331-1334 (1979)</i> <i>Comment : R, dR. 120 keV Mg, Al, P, S, Cl, K, Ar, Cr, Mn, Cu, Zn, Ga, As, Br, Kr, Rb, Ag, In, Sn, Sb, Te, I, Xe, Cs, Ba, Pr, Au, Hg, Tl, Pb, Bi -&gt; Be, C, Al, Si</i>	<b>1979-Sant</b>
<b>1979</b>	Ward, D. Andrews, H. R. Mitchell, I. V. Lennard, W. N. Walker, R. B. <b>'Systematics for the Z1-Oscillation in Stopping Powers of Various Solid Materials'</b> <i>Can. J. Phys., 57, 645-656 (1979).</i> <i>Comment : S. (vel.=0.18-0.22 cm/ns) C, N, O, F, Ne, Na, Mg, Al, Si, P, S, Cl, Ar, K, Ca -&gt; C, Al, Ni, Ag, Au</i>	<b>1979-Ward</b>
<b>1980</b>	Sofield, C. J. Cowern, N. E. B. Freeman, J. M. <b>'Charge-Exchange Effects in Energy-Loss Straggling'</b> <i>Nucl. Inst. Methods, 170, 221-225 (1980)</i> <i>Comment : R, dR. 0-50 MeV Atomic Numbers 1-16 -&gt; Al</i>	<b>1980-Sofi</b>
<b>1983</b>	Wilson, R. G. Jamba, D. M. Deline, V. R. Evans, C. A. Park, Y. S. <b>'Depth Distributions of Sulfur Implanted into GaAs as a Function of Ion Energy, Ion Fluence, and Annealing Temperature and Encapsulation'</b> <i>J. Appl. Phys., 54, 3849-3854 (1983)</i> <i>Comment : R. S (40-600 keV) -&gt; GaAs</i>	<b>1983-Wils</b>
<b>1986</b>	Lennard, W. N. Geissel, H. Phillips, D. Jackson, D. P. <b>'Heavy Ion Straggling: Possible Evidence for Inner-Shell Excitation'</b> <i>Phys. Rev. Letters, 57, 318-320 (1986)</i> <i>Comment : dS.F, Ne, Na, Mg, Al, Si, P, S, Cl, Ar, K, Sc (16 keV/amu) -&gt; C</i>	<b>1986-Lenn</b>
<b>1988</b>	Gardes, D. Bimbot, R. DellaNegra, S. Dumail, M. Kubica, B. <b>'Interaction of Heavy Ion Beams with a Hydrogen Plasma: Plasma Lens Effect and Stopping Power Enhancement'</b> <i>Europhys. Lett., 8, 701-705 (1988)</i> <i>Comment : S, C, S (2 MeV/amu) -&gt; H (plasma)</i>	<b>1988-Gard</b>

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<b>1988</b>	Wilson, R. G. <b>'(111) Random and (110) Channeling Implantation Profiles and Range Parameters in HgCdTe'</b> <i>J. Appl. Phys., 63, 5302-5311 (1988)</i> <i>Comment : R, dR. 45 Ions (H to Ta) at 100-700 keV -&gt; HgCdTe</i>	<b>1988-Wils</b>
<b>1988</b>	Wilson, R. G. <b>'Ion Implantation and SIMS Profiling of Impurities in II-VI Materials HgCdTe and CdTe'</b> <i>J. Crystal Growth, 86, 735-743 (1988)</i> <i>Comment : R, dR. 52 Ions (H-Hg) at 100-700 keV -&gt; CdTe, HgCdTe</i>	<b>1988-Wils2</b>
<b>1989</b>	Tikkanen, P. <b>'Electronic Stopping Power of Ta for Z=11-18 Atoms at Energies 0-0.8 MeV/amu'</b> <i>Nucl. Inst. Methods, B36, 103 (1989)</i> <i>Comment : S. Na, Mg, Al, Si, P, S, Cl, Ar (0-0.8 MeV/amu) -&gt; Ta</i>	<b>1989-Tikk</b>
<b>1995</b>	Randhawa, G. S. Garg, A. K. Virk, H. S. <b>'Range Study of Heavy Ions in Plastic Track Detectors'</b> <i>Rad. Meas. (UK), 24, 197-199 (1995)</i> <i>Comment : R. Heavy Ions (10-17 MeV/amu) -&gt; Lexan</i>	<b>1995-Rand</b>
<b>1996</b>	Eriksson, J. Kopniczky, J. Demirev, P. Papaleo, R. M. Brinkmalm, G. <b>'Damage Cross-Sections and Surface Track Dimensions of Biomolecular Surfaces Bombarded by Swift Heavy Ions'</b> <i>Nucl. Inst. Methods, B107, 281-286 (1996)</i> <i>Comment : S. S, Cu, Br, I (1.1 cm/ns) -&gt; Biological targets (peptides).</i>	<b>1996-Erik</b>
<b>1996</b>	Gelfort, S. Kerkow, H. Stolle, R. Petukhov, V. P. Romanowski, E. A. <b>'Angular Dependence of the Electronic Energy Loss for Low Energy Heavy Ions under Channeling Conditions'</b> <i>Nucl. Inst. Methods, B115, 315-318 (1996)</i> <i>Comment : S. Channeling of ions He to Kr in Si &lt;110&gt;</i>	<b>1996-Gelf</b>
<b>1996</b>	Hari, K. V. Pathak, A. P. Sharma, S. K. Shyam, K. Nath, N. <b>'Energy Loss of MeV Heavy Ions in Carbon'</b> <i>Nucl. Inst. Methods, B108, 223-226 (1996)</i> <i>Comment : S. Z1 (O - Cu) at 0.1-1.0 MeV/amu -&gt; C</i>	<b>1996-Hari</b>
<b>2001</b>	Diwan, P. K. Kumar, S. Singh, G. Singh, L. <b>'Energy Loss of Heavy Ions in Gases: A Comparative Study'</b> <i>Rad. Meas., 33, 193-202 (2001)</i> <i>Comment : S. Ne, S, Cl, Ar, Cu, Kr (1 - 80 MeV/u) -&gt; H, He, N, Ar, Ne, Xe, CH4, C4H10, CO2, CF4</i>	<b>2001-Diwa2</b>
<b>2002</b>	Geissel, H. Weick, H. Scheidenberger, C. Bimbot, R. Gardes, D. <b>'Experimental Studies of Heavy-Ion Slowing Down in Matter'</b> <i>Nucl. Inst. Methods, B195, 3-54 (2002)</i> <i>Comment : S. Summary of 18 Heavy Ion Stopping in 26 Targets</i>	<b>2002-Geis</b>

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<b>Year</b>	Sun, G. Döbeli, M. Müller, A.M. Stocker, M. Suter, M. <b>2007</b> 'Energy loss and straggling of heavy ions in silicon nitride in the low MeV energy range' <i>Nucl. Instrum. Methods B 256 (2007) 586 (2007)</i> Comment : S, dS. Li, B, C, O, S, Fe (0.4 - 4 MeV) ->silicon nitride Si <sub>3</sub> N <sub>3</sub> .1	2007-Sun